

SUBSTITUTE FORM PTO-1449
(MODIFIED)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

07653/020002

SERIAL NO.

318,159

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Use several sheets if necessary)

APPLICANT

Rhodes

FILING DATE

5/25/99

GROUP

2811

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>SKM</i>	AA	5	7	0	2	9	7	6	12/30/97	Schuegraf et al.			
	AB	5	6	9	3	9	7	1	12/02/97	Gonzalez			
	AC	5	4	9	2	8	5	3	02/20/96	Jeng et al.			
	AD	5	4	3	3	7	9	4	07/18/95	Fazan et al.			
	AE	5	3	9	7	9	0	8	03/14/95	Dennison et al.			
<i>SKM</i>	AF	5	2	5	0	4	5	0	10/05/93	Lee et al.			
	AG												
	AH												
	AI												
	AJ												
	AK												

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

<i>SKM</i>	AQ	S. Nag et al., "Comparative Evaluation of Gap-Fill Dielectrics in Shallow Trench Isolation for Sub-0.25µm Technologies", IEEE 1996, pp. 841-844						
<i>SKM</i>								
<i>SKM</i>	AR	S. Mendis et al., "Progress In CMOS Active Pixel Image Sensors", SPIE Vol. 2172, pp. 19-29 Feb. 1994,						
		pp. 19-29,						
<i>SKM</i>	AS	S.B. Campana, "Techniques for Evaluating Charge Coupled Imagers", Optical Engineering, May-June 1977,						
		Vol. 16, No. 3, pp. 167-274						

EXAMINER

G. Munson

DATE CONSIDERED

18 JANUARY 2000

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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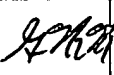

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BA						
	BB						
	BC						
	BD						
	BE						
	BF						
	BG						
	BH						
	BI						
	BJ						
	BK						

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							YES	NO
	BL							
	BM							
	BN							
	BO							
	BP							

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

	BQ	S. Mendis et al., "CMOS Active Pixel Image Sensors for Highly Integrated Imaging Systems", IEEE 1997,
		pp. 187-197
	BR	S. Mendis et al., "A 128 x 128 CMOS Active Pixel Image Sensor for Highly Integrated Imaging Systems",
		IEEE 1993, pp. 583-586
	BS	

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